

**Search Notes**

Application/Control No.

10/774,690

Examiner

Leith A. Al-Nazer

Applicant(s)/Patent under  
Reexamination

TANAKA ET AL.

Art Unit

2821

**SEARCHED**

Class	Subclass	Date	Examiner
315	111.21	7/22/2005	LA
422	186.04	7/22/2005	LA
422	186.18	7/22/2005	LA
423	210	7/22/2005	LA
423	235	7/22/2005	LA
423	245.1	7/22/2005	LA

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Text Search (see attached printout)	7/22/2005	LA